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APR -3 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

TECHNOLOGY CENTER 2800

In re Application of:
Levy et al.

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Group Art Unit: 2862
Examiner: Unknown

Serial No. 09/957,468

Atty. Dkt. No. 5589-02305

Filed: September 20, 2001

For: METHODS AND SYSTEMS FOR
DETERMINING A CRITICAL
DIMENSION, A PRESENCE OF
DEFECTS, AND A THIN FILM
CHARACTERISTIC OF A SPECIMEN

I hereby certify that this correspondence is being deposited
with the U.S. Postal Service as First Class Mail in an envelope
addressed to: Assistant Commissioner for Patents, Washington,
D.C. 20231, on the date indicated below:

3/28/03
Date

Pamela Gerik
Pamela Gerik

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Applicant requests consideration of ☒ the references listed on the attached Form PTO-1449
and/or ☐ the additional information identified below in paragraph 3. A copy of each reference listed on
the Form PTO-1449 is enclosed.

1. This Information Disclosure Statement is submitted:

- a. ☐ within 3 months of the filing date of a national application other than a continued prosecution application under § 1.53(d);
☐ within 3 months of the date of entry of the national stage as set forth in § 1.491 in an International application;
☒ before the mailing date of a first Office Action on the merits; or
☐ before the mailing of a first Office Action after the filing of a request for continued examination under § 1.114.
- b. ☐ after the events of above paragraph 1a and prior to the mailing date of a final Office Action or Notice of Allowance, and thus: ☐ the certification of paragraph 2 below is provided, or ☐ a fee of \$180.00 is enclosed.
- c. ☐ after the mailing date of a final Office Action or a Notice of Allowance and prior to payment of the issue fee, and thus: the certification of paragraph 2 below is provided and a fee of \$180.00 is enclosed.

2. It is hereby certified:

- ☐ that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
- ☐ that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in § 1.56 (c) more than three months prior to the filing of the Statement.

3. ☐ Consideration of the following additional information (including any co-pending or abandoned U.S. applications, prior uses and/or sales, etc.) is requested:

4. For each non-English language reference listed on the attached Form PTO-1449:

- ☐ reference is made to an English language translation submitted herewith, and/or
- ☐ reference is made to a foreign patent office search report (in the English language) submitted herewith, and/or
- ☐ reference is made to an English language translation of a foreign patent office search report submitted herewith, and/or
- ☐ reference is made to the concise explanation contained in the specification of the present application at page(s) _____, and/or
- ☐ reference is made to the concise explanation set forth below:

5. ☐ Applicant also offers the following comments for the Examiner's consideration:

6. ☐ Also enclosed is a copy of a foreign search report citing these references.

7. ☐ The listed documents were brought to the attention of the Applicant(s) after payment of the issue fee in the captioned case. The documents were cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. Applicant(s) request this Information Disclosure Statement and attached Form PTO-1449 be placed in the file of the captioned application.

8. ☐ Applicant(s) requests that the Information Disclosure Statement and attached Form PTO-1449 and references, which are being filed before the grant of the patent and pursuant to 37 C.F.R. § 1.97(i), be placed in the file of the captioned application.

If any required fees are missing, the Commissioner is authorized to charge said fees to Conley, Rose & Tayon, P.C. Deposit Account No. 03-2769/5589-02305.

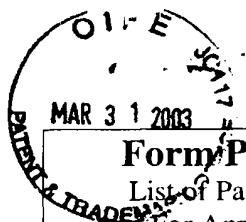
Respectfully submitted,



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Reg. No. 50,484
Agent for Applicant(s)

CONLEY, ROSE & TAYON, P.C.
P. O. Box 398
Austin, Texas 78767
(512) 476-1400

Date: 3/28/03



Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02305 APPLICANT: Levy et al. FILING DATE: September 20, 2001	SERIAL NO. 09/957,468 GROUP: 2862
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U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	D1	4631416	12/1986	Trutna, Jr.			
	D2	5114235	5/1992	Suda et al.			
	D3	5182455	1/1993	Muraki			
	D4	5182610	1/1993	Shibata			
	D5	5189494	2/1993	Muraki			
	D6	5316984	5/1994	Leourx			
	D7	5327221	7/1994	Saitoh et al.			
	D8	5340992	8/1994	Matsugu et al.			
	D9	5414514	5/1995	Smith et al.			
	D10	5666196	9/1997	Ishii et al.			
	D11	5783342	7/1998	Yamashita et al.			
	D12	5801390	9/1998	Shiraishi			
	D13	6046094	4/2000	Jost et al.			
	D14	6077756	6/2000	Lin et al.			
	D15	6079256	6/2000	Bareket			
	D16	6128089	10/2000	Ausschnitt et al.			
	D17	6153886	11/2000	Hagiwara et al.			
	D18	6177330	1/2001	Yasuda			
	D19	6255189	7/2001	Muller et al.			
	D20	6301011	10/2001	Fung et al.			
	D21	6388253	5/2002	Su			
	D22	6421124	7/2002	Matsumoto et al.			
	D23	6462818	10/2002	Bareket			
	D24	6476920	11/2002	Scheiner et al.			
	D25	6486492	11/2002	Su			
	D26	6486954	11/2002	Mieher et al.			
	D27	2002/0018217	2/2002	Weber-Grabau et al.			

EXAMINER: _____ DATE CONSIDERED: _____

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.

Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-02305	SERIAL NO. 09/957,468
	APPLICANT: Levy et al.	GROUP: 2862
	FILING DATE: September 20, 2001	

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	D28	2002/0149782	10/2002	Raymond			
	D29	2002/0158193	10/2002	Sezginer et al.			
	D30	2002/0192577	12/2002	Fay et al.			

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
	D31	02/15238	2/2002	WO			
	D32	02/25723	3/2002	WO			
	D33	02/069390	9/2002	WO			

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	D34	McNeil et al., "Scatterometry Applied to Microelectronics Processing," Microlithography World, November/December 1992, pp. 16-22.
	D35	Raymond et al., "Metrology of subwavelength photoresist gratings using optical scatterometry," J. Vac. Sci. Technol. B 13(4), Jul/Aug 1995, pp. 1484-1495.
	D36	Wittekoek et al., "In-process Image Detecting Technique for Determination of Overlay, and Image Quality for ASM-L Wafer Stepper," SPIE Vol. 1674 Optical/Laser Microlithography V (1992), pp. 594-608.

EXAMINER: _____ DATE CONSIDERED: _____

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